

Search Notes

Application/Control No.

09/716,415

Examiner

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Applicant(s)/Patent under
Reexamination

TAKEDA ET AL.

Art Unit

2142

SEARCHED

Class	Subclass	Date	Examiner
709	203	9/23/2007	HN
709	206	9/23/2007	HN
705	30	9/23/2007	HN
455	556.2	9/23/2007	HN
455	557	9/23/2007	HN
358	1.15	9/23/2007	HN
updated	search	9/28/2007	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	9/23/2007	HN
Limited classified search: 709/203, 206; 705/30; 455/556.2, 557; 358/1.15 (see search history printout report)	9/23/2007	HN